

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	113	ink near3 (drop\$4) near3 (size or diameter) with (um or micron or micrometer or nm or nano or nanometer)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/24 10:18
L2	86	ink near3 (drop\$4) near3 (size or diameter) with (um or micron or micrometer or nm or nano or nanometer) same print\$3	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/24 10:18
L3	4	ink near3 (drop\$4) near3 (size or diameter) with (um or micron or micrometer or nm or nano or nanometer) same print\$3 and (intaglio or gravure)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/24 10:18
L4	28	ink near3 (drop\$4) near3 (size or diameter) with (nm or nano or nanometer) same print \$3	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/24 10:19
L7	4	(afm or "atomic force microscope" or "atomic force microscopy") with (barcode or "bar code") with (read\$4 or decod \$4)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/24 10:55
L8	1	10/533,375	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/24 10:56
L9	264	(afm or "atomic force microscope" or "atomic force microscopy" or microscop\$3) with (barcode or "bar code") with (read\$4 or decod \$4)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/24 10:56

L10	240	(afm or "atomic force microscope" or "atomic force microscopy" or microscop\$3) with (barcode or "bar code") near3 (read\$4 or decod \$4)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/24 10:56
L11	4	(afm or "atomic force microscope" or "atomic force microscopy" or "atomic force") with (barcode or "bar code") with (read\$4 or decod \$4)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/24 10:57
L12	23162	(afm or "atomic force microscope" or "atomic force microscopy" or "atomic force")	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/24 10:58
L13	17	(afm or "atomic force microscope" or "atomic force microscopy" or "atomic force") with (barcode or "bar code")	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/24 10:58
L14	6	delitz.in.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/24 11:22
L15	218	(barcode or "bar code") with (polymer or "cross linked polymer" or "cross-linked polymer")	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/24 11:31
L16	4	("atomic force microscope" or afm) with read\$3 near5 (barcode or "bar code")	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/24 11:47
L17	4	("atomic force microscope" or afm) with read\$3 with (barcode or "bar code")	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/24 11:48
L18	32	("atomic force microscope" or afm or "atomic force" or "microscopy) with read \$3 with (barcode or "bar code")	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/24 11:48
L19	1	"20040038310".pn.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/24 12:22

S1	2	("20020012689" "5995704").pn.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/22 20:06
S2	10	(barcode or "bar code") with ("sub micron" or (less near3 micron))	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/22 20:07
S3	39	(barcode or "bar code") with ("sub micron" or (less near3 micron) or micrometer or um)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 09:34
S4	2	("7185816" "20040245343").pn.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 09:47
S5	1343	("3d" or "3-d" or "three-dimensional" or "three dimensional" or "tri dimensional" or "tri-dimensional") with (barcode or "bar code")	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 10:08
S6	379	("3d" or "3-d" or "three-dimensional" or "three dimensional" or "tri dimensional" or "tri-dimensional") with (barcode or "bar code") and (micron or um or micrometer)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 10:08
S7	285	("3d" or "3-d" or "three-dimensional" or "three dimensional" or "tri dimensional" or "tri-dimensional") with (barcode or "bar code") and (micron or um or micrometer) with (bar or space or element or width or height or length or dimension)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 10:09
S8	379	((3d" or "3-d" or "three-dimensional" or "three dimensional" or "tri dimensional" or "tri-dimensional") not ("FIG." adj 3d)) with (barcode or "bar code") and (micron or um or micrometer)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 10:10

S9	68	("3d" or "3-d" or "three-dimensional" or "three dimensional" or "tri dimensional" or "tri-dimensional") with (barcode or "bar code") and (micron or um or micrometer or nm or nanometer) same silicon	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 10:11
S10	1	("3d" or "3-d" or "three-dimensional" or "three dimensional" or "tri dimensional" or "tri-dimensional") with (barcode or "bar code") and (micron or um or micrometer or nm or nanometer) same silicon same (bar or space or element)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 10:12
S11	1	"5298731".pn.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 10:32
S12	4	(barcode or "bar code") same pattern\$3 same (3d or "three-dimensional" or "three-dimensional" or "3-d") same (nanometer or nm or micron or um) same (silicon or polymer)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 10:40
S13	6	(barcode or "bar code") same (etch\$4 or fus\$4 or pattern\$3 or ablat\$4 or burn\$4 or laser) same (3d or "three-dimensional" or "three-dimensional" or "3-d" or orthogonal or dimension \$3 or axis) same (nanometer or nm or micron or um) same (silicon or polymer)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 10:49

S14	1033	(barcode or "bar code" or indicia or mark\$3 or label) same (etch\$4 or fus\$4 or pattern\$3 or ablat\$4 or burn\$4 or laser or form\$4 or mark \$3) same (3d or "three-dimensional" or "three-dimensional" or "3-d" or orthogonal or dimension \$3 or axis) same (nanometer or nm or micron or um) same (silicon or polymer or substrate or sheet or base)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 10:55
S15	1303	(barcode or "bar code" or indicia or identification or identifier or id or code or information or label) same (etch\$4 or fus\$4 or pattern\$3 or ablat\$4 or burn\$4 or laser or form\$4 or mark\$3) same (3d or "three-dimensional" or "three-dimensional" or "3-d" or orthogonal or dimension \$3 or axis) same (nanometer or nm or micron or um) same (silicon or polymer or substrate or sheet or base)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 10:56
S16	664	(barcode or "bar code" or indicia or identification or identifier or id or code or information or label) with (etch\$4 or fus\$4 or pattern\$3 or ablat\$4 or burn\$4 or laser or form \$4 or mark\$3) same (3d or "three-dimensional" or "three-dimensional" or "3-d" or orthogonal or dimension\$3 or axis) same (nanometer or nm or micron or um) same (silicon or polymer or substrate or sheet or	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 10:56

		base)				
S17	73	S16 and ("235"/\$.ccls. "216"/\$.ccls. "257"/\$.ccls. "438"/\$.ccls.)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 10:57
S18	581	(etch\$3 or pattern\$4 or trench\$4 or fus\$4 or laser or burn\$3 or photolithograp\$6) with (barcode or "bar code" or code or coding) same (substrate or sheet or silicon or polymer) and ("235"/\$.ccls. "216"/\$.ccls. "257"/\$.ccls. "438"/\$.ccls.) and (nanometer or nm or micrometer or micron or um)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 13:05
S19	140	("977"/\$.ccls. "430"/\$.ccls. "216"/\$.ccls. "264"/\$.ccls.) and (barcode or "bar code" or code) same (3d or "3-d" or "three dimensional")	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 13:30
S20	10307	(semiconductor or die or dice or chip or IC) and (align\$4 or mark\$3 or cod\$3) with (microns or micrometer or nanometer)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 13:31
S21	14	("4047000" "4061174" "4162340" "4175236" "4536421" "4625101" "4900637" "4941522" "5160383" "5329985" "5786028" "6222452").PN. OR ("6666255").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2009/04/23 13:45
S22	85	("20010005570" "20010012137" "20010038451" "20020018430" "20020060659" "20020067265" "20020075481" "20020122878" "20030015591" "20030031861" "20030084305" "20040000787" "20040020995"	US-PGPUB; USPAT; USOCR	OR	ON	2009/04/23 13:46

S23	764	"20040027630" "4316665" "4333006" "4339168" "4343874" "4364627" "4429946" "4547002" "4597814" "4684795" "4725111" "4728377" "4778262" "4832445" "4900111" "4913504" "4921319" "4933120" "4969700" "5003915" "5044707" "5071597" "5083850" "5085514" "5116548" "5128779" "5142383" "5145212" "5194971" "5237160" "5245170" "5267756" "5306899" "5310222" "5331143" "5336871" "5380047" "5393099" "5411298" "5422744" "5432329" "5461239" "5524758" "5634669" "5644412" "5661289" "5772248" "5786587" "5801857" "5856048" "6086708" "6100804" "6130613" "6147662" "6149059" "6181287" "6214443" "6220333" "6259369" "6268893" "6280544" "6280891" "6318636" "6321986" "6328209" "6354501" "6415978" "6436483" "6523750" "6582197" "6609728" "6666255"). PN. OR ("7267280"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2009/04/23 13:58	

S24	25	(nano or nanometer or nm or micrometer or micron or um) with (barcode or "bar code") same (3d or "3-d" or "three dimensional" or orthogonal\$4 or perpendicular\$4)	US-PGPUB; USPAT; USOOR	OR	ON	2009/04/23 13:59
S25	1	"6803291".pn.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 14:34
S26	2	"6803291".pn. "6083806".pn.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 14:40
S27	0	mirco adj (barcode or "bar code")	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 14:42
S28	22	microbarcode	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 14:42
S29	40	(barcode or "bar code") with align\$4 same (micron or micrometer or um or nano or nm or nanometer)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 14:44
S30	4986	(code or pattern or indicia or barcode or "bar code") with align\$4 same (micron or micrometer or um or nano or nm or nanometer)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 14:45
S31	1348	(code or pattern or indicia or barcode or "bar code") with align\$4 same (micron or micrometer or um or nano or nm or nanometer) same (dimension\$3 or orthogonal\$4 or normal or perpendicular\$3)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 14:49
S32	649	("977"/\$.ccls. "430"/\$.ccls. "216"/\$.ccls. "264"/\$.ccls. "248"/\$.ccls. "257"/\$.ccls. "235"/\$.ccls.) and S31	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 14:56

S33	91	intaglio with print\$3 with (um or nm or nano or micrometer or micron or nanometer)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 15:07
S34	4	(micro near10 barcode) same micrometer\$1	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 15:12
S35	30	(barcode or "bar code") same (afm or "atomic force microscopy")	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 15:18
S36	1	"20040245343".pn.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 15:24
S37	1	"5499731".pn.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 15:25
S38	0	(submicron or "sub-micron") with intaglio	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 15:28
S39	77	("micron" or um or micrometer) with intaglio	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 15:28
S40	61	("micron" or um or micrometer) with intaglio same print\$3	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 15:28
S41	1	"20040245343".pn.	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 15:29
S42	0	intaglio with ink near3 droplet near3 siz\$3	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 15:50
S43	0	intaglio with ink near3 drop\$3 near3 siz\$3	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 15:51
S44	13	intaglio with ink near3 siz\$3	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 15:51
S45	49	intaglio with (nano or nm or nanometer) with print\$3	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 15:55
S46	27638	"sub micron"	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 16:00
S47	12	"sub micron" same (barcode or "bar code")	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 16:00

S48	47	nano near3 (barcode or "bar code")	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 16:01
S49	57	intaglio with print\$3 with ((nanometer or nm or um or micron or micrometer) not (wavelength))	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 16:08
S50	483	("sub micron" or micron or micrometer or nano or nanometer or nm or um) with (barcode or code or "bar code" or coding) with (element or portion or unit)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2009/04/23 16:21

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